fss fast SiC semiconductor

FF07300M2

Product Datasheet

Silicon Carbide MOSFET

750V, 300mΩ SiC MOSFET – Falcon M2 Series

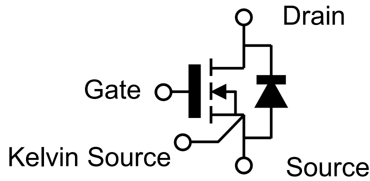
Features

- Optimized $R_{DS(on)}$ with Rapid Switching Behavior
- Compatible with Standard Gate Drivers
- High Avalanche Endurance Capability
- Optimized for High Power Density Applications
- RoHS Compliant and Halogen Free

Potential Applications

- Switching Mode Power Supply
- PFC & DC/DC Converter
- Portable Adaptor
- Renewable Energy
- Power Inverter
- Motor Driver

Product Information:



Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems
- High Reliability

Product Information	Packaging Type	
	TO-252	PQFN 5x6
	Tab, 1, 2, 3	1 2 3 4, 8 7 6 5
Gate	1	4
Drain	2, Tab	5, 6, 7, 8
Source	3	1, 2, 3
Kelvin Source	--	--
Part Number	FF07300M2A	FF07300M2B
Marking	FF07300M2	FF07300M2
Continuous Drain Current	11A	11A
Power Dissipation	82W	98W

Key Performance Parameters

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS} @$T_{j(max)}$	750	V
Recommended Gate-Source Turn-On Voltage	V_{GS}	12~15	
Drain-Source On-State Resistance	$R_{DS(on)}$	300	mΩ
Pulse Drain Current	$I_{D, pulse}$	15	A
Avalanche Energy	E_{AS}	40	mJ
Gate Charge	Q_G	10.6	nC
Output Capacitive Charge	Q_{oss}	9.9	
Junction & Storage Temperature	T_j, T_{stg}	-55 to 175	°C

For further information about comparable products, please contact (www.fastsic.com).

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Maximum Ratings: (Tj = 25°C, unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Voltage	V_{DSS}	750	--	--	V	V_{GS}=0V, I_D=1mA
Continuous Drain Current	I_D	--	--	11	A	V_{GS}=15V, T_C=25°C (By package type[1])
				8	A	V_{GS}=15V, T_C=100°C (By package type[1])
Continuous Body Diode Current	I_S	--	--	9	A	V_{GS}=0V, T_C=25°C (By package type[1])
Pulse Drain Current	$I_{D, pulse}$	--	--	15	A	Per SOA
Avalanche Energy, Single Pulse	E_{AS}	--	--	40	mJ	L=25mH
Operate Gate Source Voltage	$V_{GS, op}$	-8	--	12~15	V	Recommended operating values
Transient Gate Source Voltage	$V_{GS, tran.}$	-9	--	19	V	Transient operating limit (AC f > 1Hz, pulse width < 100ns)
Junction Temperature	T_j	-55	--	175	°C	
Storage Temperature	T_{stg}	-55	--	175	°C	
Soldering Temperature	T_L	--	--	260	°C	

[1] *Per figure section 2~6*

Electrical Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
DC Characteristics (at T_j = 25°C, unless otherwise specified)						
Drain-source Breakdown Voltage	$V_{(BR)DSS}$	750	--	--	V	V_{GS}=0V, I_D=1mA, T_j=25°C
Drain-Source On-State Resistance	$R_{DS(on)}$	--	300	--	mΩ	V_{GS}=15V, I_D=2A, T_j=25°C
		--	433	--	mΩ	V_{GS}=15V, I_D=2A, T_j=175°C
		--	390	--	mΩ	V_{GS}=12V, I_D=2A, T_j=25°C
		--	472	--	mΩ	V_{GS}=12V, I_D=2A, T_j=175°C
Gate-Source Threshold Voltage	V_{th}	--	2.5	--	V	V_{GS}=V_{DS}, I_D=1mA
Zero Gate Voltage Drain Current	I_{DSS}	--	<1	1000	µA	V_{DS}=750V, V_{GS}=0V, T_j=25°C
Gate-Source Leakage Current	I_{GSS}	--	--	100	nA	V_{GS}=15V, V_{DS}=0V
Body Diode Forward Voltage	V_{SD}	--	2.8	--	V	V_{GS}=0V, I_S=1A, T_j=25°C
		--	4.1	--	V	V_{GS}=0V, I_S=1A, T_j=175°C
AC Characteristics (at T_j = 25°C, unless otherwise specified)						
Input Capacitance	C_{iss}	--	284.3	--	pF	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
Output Capacitance	C_{oss}	--	13.5	--	pF	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
Reverse Capacitance	C_{rss}	--	1.4	--	pF	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
Effective Output Capacitance, energy related	$C_{o(er)}$[1]	--	17.2	--	pF	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
Effective Output Capacitance, time related	$C_{o(tr)}$[2]	--	24.8	--	pF	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
C_{oss} Stored Energy	E_{oss}	--	1.4	--	µJ	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
Output Capacitive Charge	Q_{oss}	--	9.9	--	nC	V_{DS}=400V, V_{GS}=0V, f=250kHz, V_{AC}=25mV
Internal Gate Resistance	$R_{G, int.}$	--	7.0	--	Ω	f=1MHz, V_{AC}=25mV

[1] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V.

[2] $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V.

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Switching Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Gate Characteristics						
Gate to Source Charge	Q_{GS}	--	2.2	--	nC	V_{DS}=400V, V_{GS}=0V/+15V, I_D=2A
Gate to Drain Charge	Q_{GD}	--	4.2	--	nC	
Total Gate Charge	Q_G	--	10.6	--	nC	
Inductive Load						
Turn On Delay Time	$t_{d(on)}$	--	TBD	--	nC	
Rise Time	t_r	--	TBD	--	nC	
Turn Off Delay Time	$t_{d(off)}$	--	TBD	--	nC	
Fall Time	t_f	--	TBD	--	nC	
Turn On Switching Energy	E_{on}	--	TBD	--	nC	
Turn Off Switching Energy	E_{off}	--	TBD	--	nC	
Body Diode Characteristics						
Forward Recovery Charge	Q_{fr}	--	TBD	--	nC	
Forward Recovery Time	t_{fr}	--	TBD	--	ns	
Peak Foreard Recovery Current	I_{frm}	--	TBD	--	A	

[1] Test are based on TO-220-3L PKG

Thermal Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Thermal Impedance, junction-case	R_{th-jc}	--	1.82	--	K/W	*TO-252*
		--	1.52	--	K/W	*PQFN 5x6*
Thermal Impedance, junction-ambient	R_{th-ja}	--	40	--	K/W	*Device on PCB, with 6 cm² of cooling area*

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1. Electrical Characteristics Diagrams

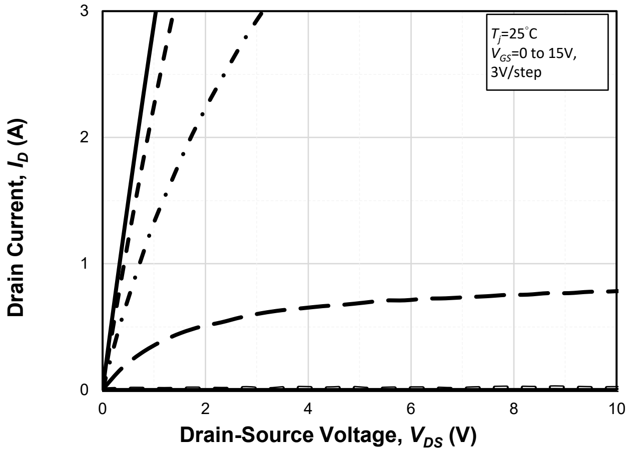

Fig. 1-1 Typical Output Characteristics at T_j=25°C

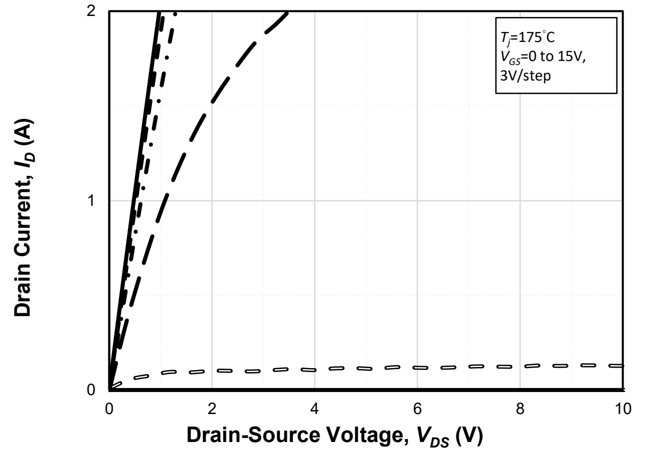

Fig. 1-2 Typical Output Characteristics at T_j=175°C

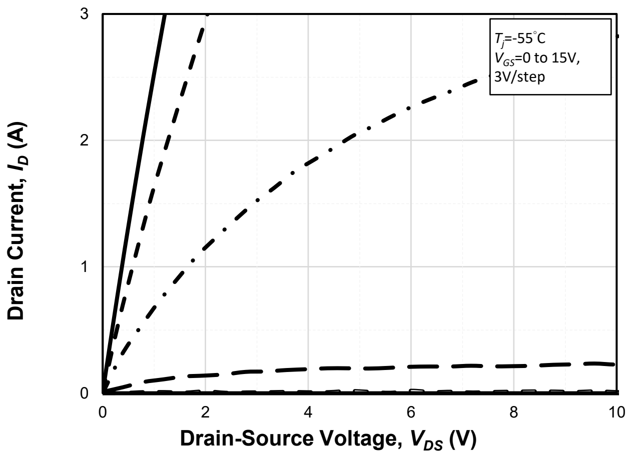

Fig. 1-3 Typical Output Characteristics at T_j=-55°C

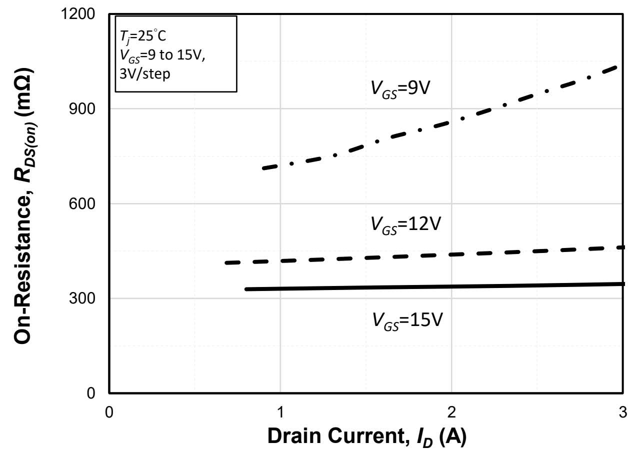

Fig. 1-4 Typ. $R_{DS(on)}$ vs. I_D with Various V_{GS}

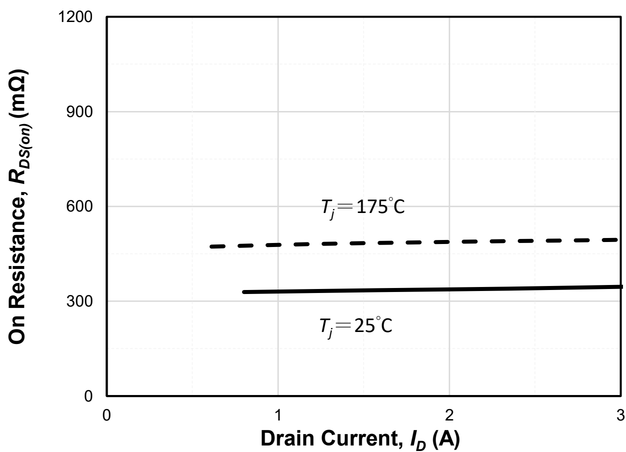

Fig. 1-5 Typ. $R_{DS(on)}$ vs. I_D with Various T_j, V_{GS}=15V

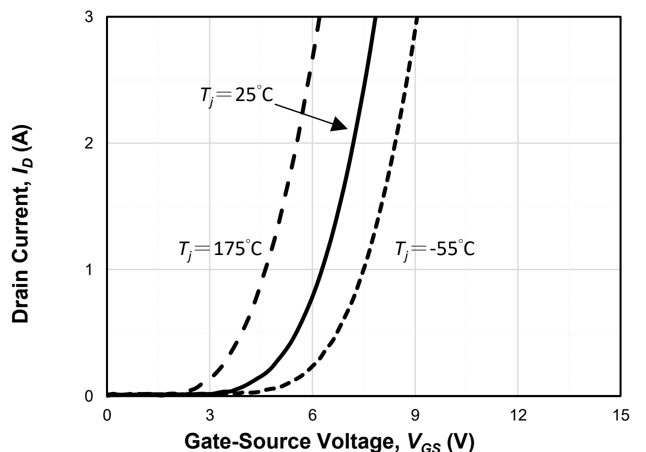

Fig. 1-6 Typ. I_D vs. V_{GS} with Various T_j, V_{DS}=10V

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1. Electrical Characteristics Diagrams

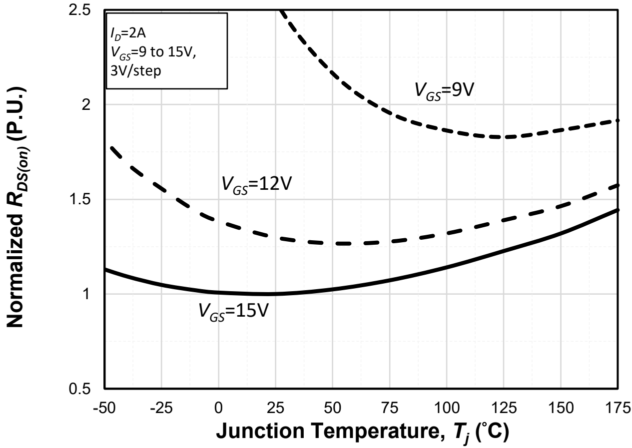

Fig. 1-7 Normalized $R_{DS(on)}$ vs. T_j with Various V_{GS}

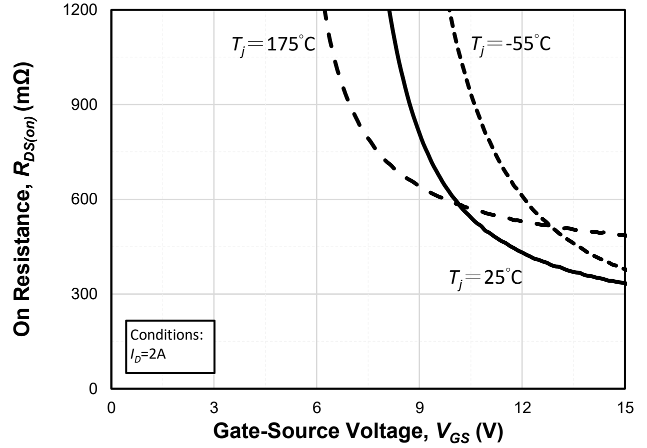

Fig. 1-8 Typ. $R_{DS(on)}$ vs. V_{GS} with Various T_j

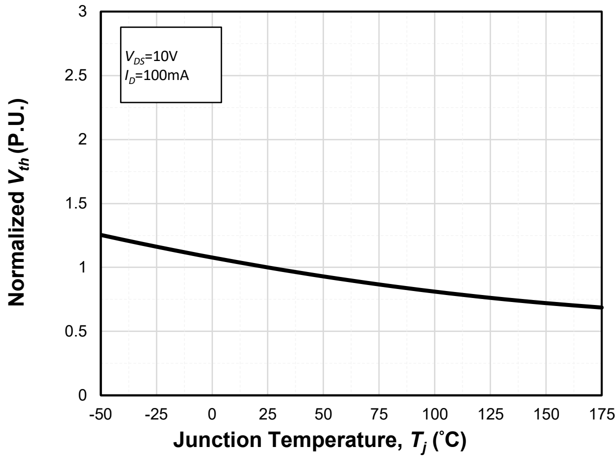

Fig. 1-9 Normalized V_{th} vs. T_j

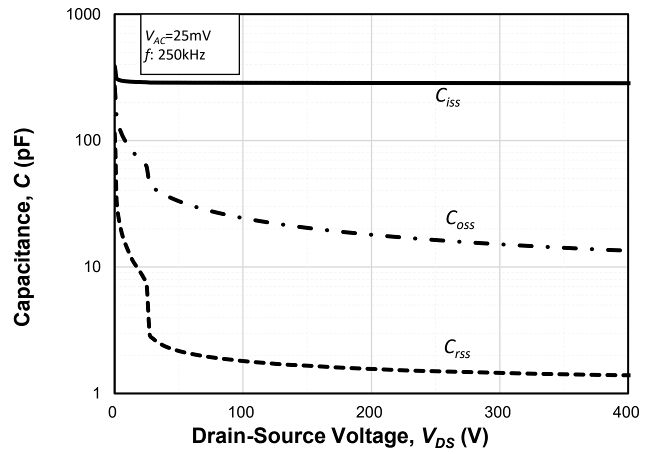

Fig. 1-10 Typ. Capacitance vs. V_{DS} at f_{sw}=250kHz

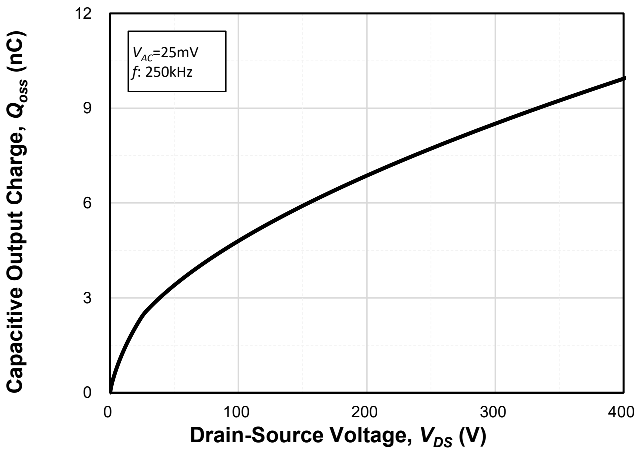

Fig. 1-11 Typ. Capacitive Output Charge at f_{sw}=250kHz

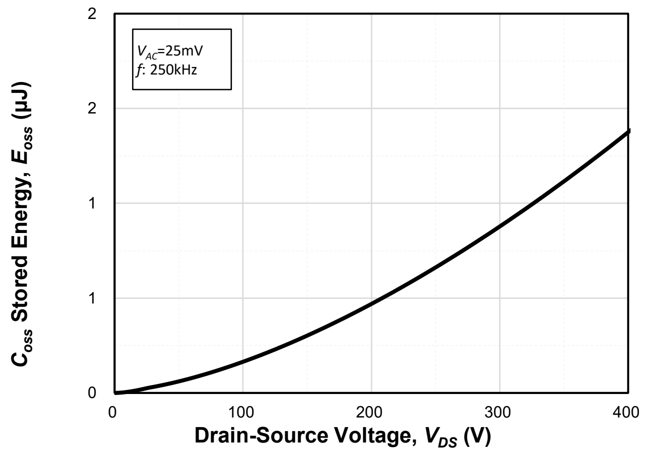

Fig. 1-12 Typ. CossStored Energy at fsw=250kHz

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1. Electrical Characteristics Diagrams

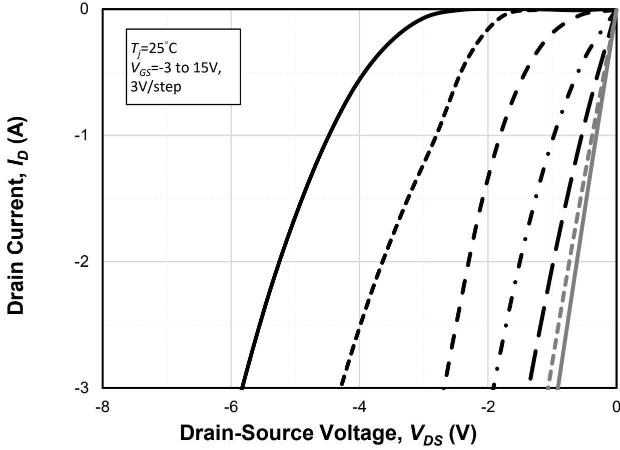

Fig. 1-13 Typical Forward Characteristics of Reverse Conduction at T_j=25°C

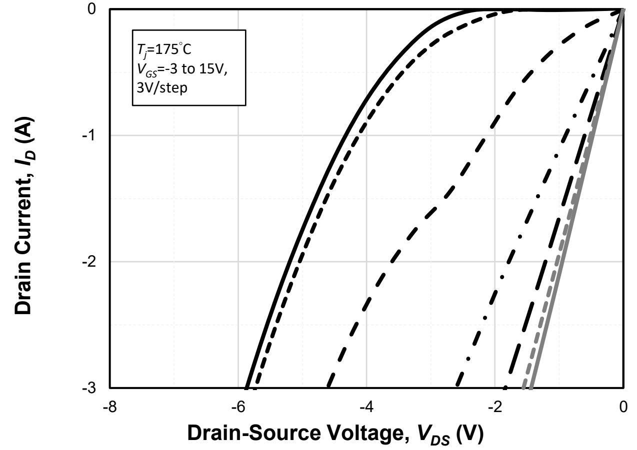

Fig. 1-14 Typical Forward Characteristics of Reverse Conduction at T_j=175°C

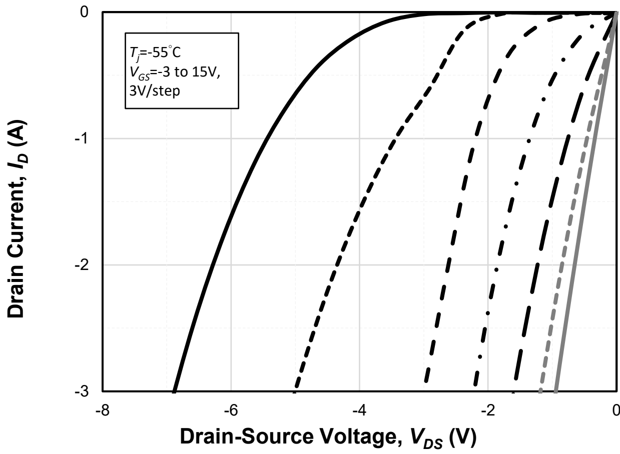

Fig. 1-15 Typical Forward Characteristics of Reverse Conduction at T_j=-55°C

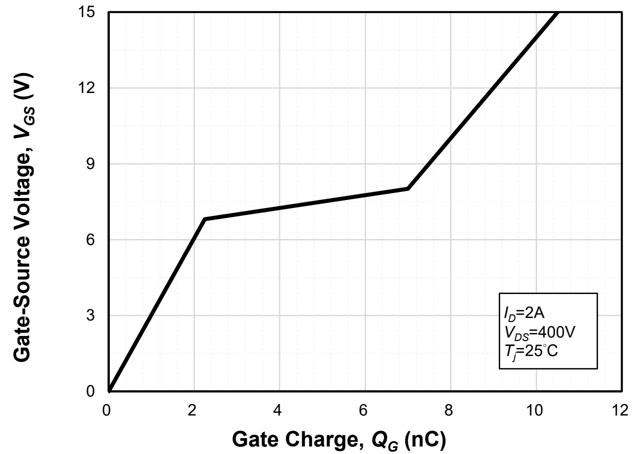

Fig. 1-16Typ. Gate Charge

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2. Drain Power Dissipation

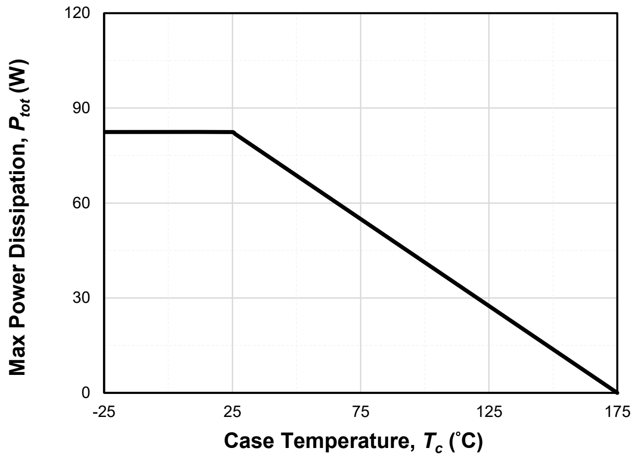

Fig. 2-1 Power Dissipation at V_{GS}=15V, T_j≤175˚C (TO-252)

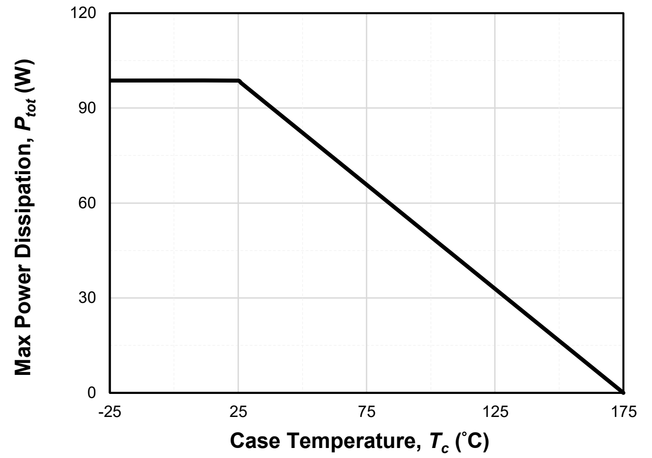

Fig. 2-2 Power Dissipation at V_{GS}=15V, T_j≤175˚C (PQFN 5x6)

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3. Drain Current Dissipation

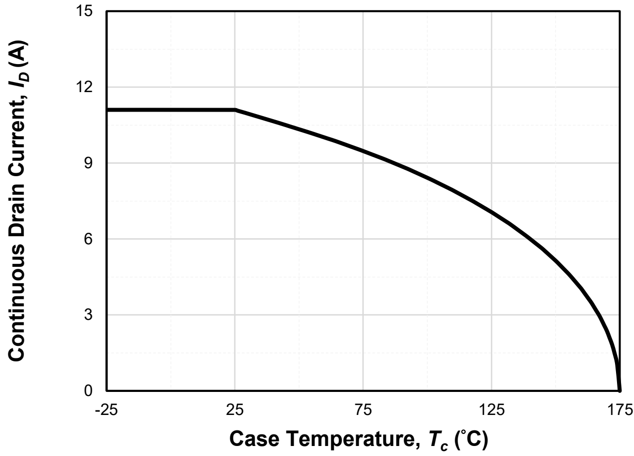

Fig. 3-1 Current Dissipation at V_{GS}=15V, T_j≤175˚C (TO-252)

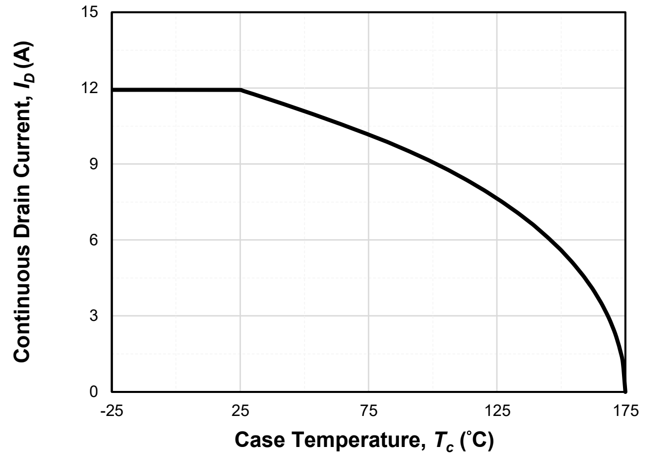

Fig. 3-2 Current Dissipation at V_{GS}=15V, T_j≤175˚C (PQFN 5x6)

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4. Body Diode Current Dissipation

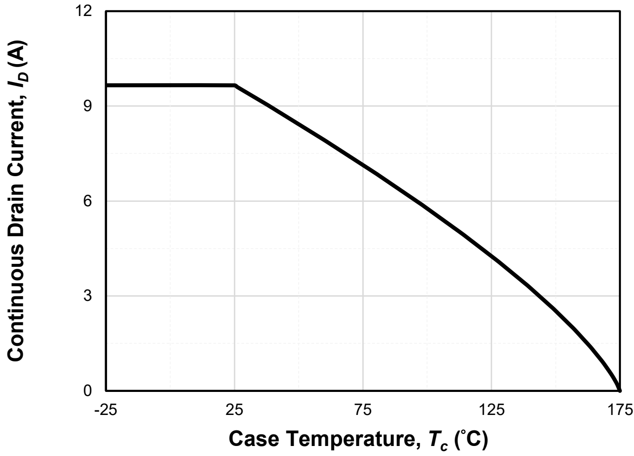

Fig. 4-1 Body Diode Current Dissipation at V_{GS}=0V, T_j≤175˚C (TO-252)

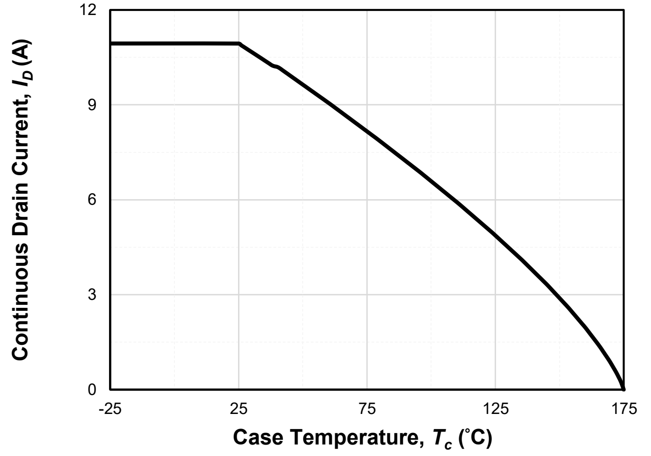

Fig. 4-2 Body Diode Current Dissipation at V_{GS}=0V, T_j≤175˚C (PQFN 5x6)

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5. Thermal Impedance

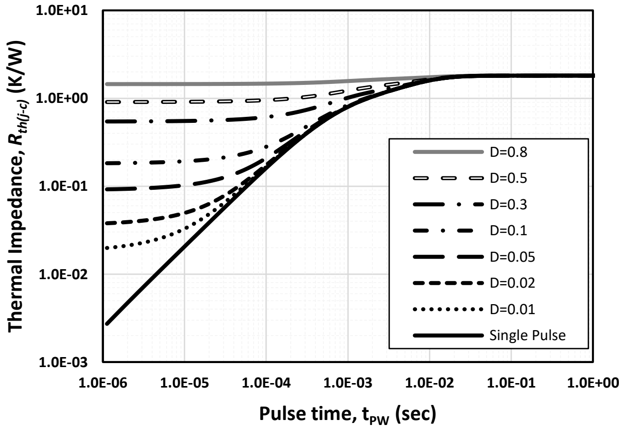

Fig. 5-1 Typ. Transient Thermal Impedance $R_{th\text{-}jc}$ (TO-252)

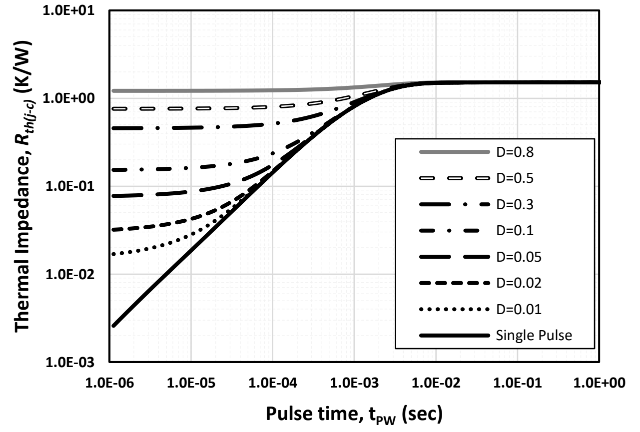

Fig. 5-2 Typ. Transient Thermal Impedance $R_{th\text{-}jc}$ (PQFN 5x6)

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6. Safe Operating Area (25˚C)

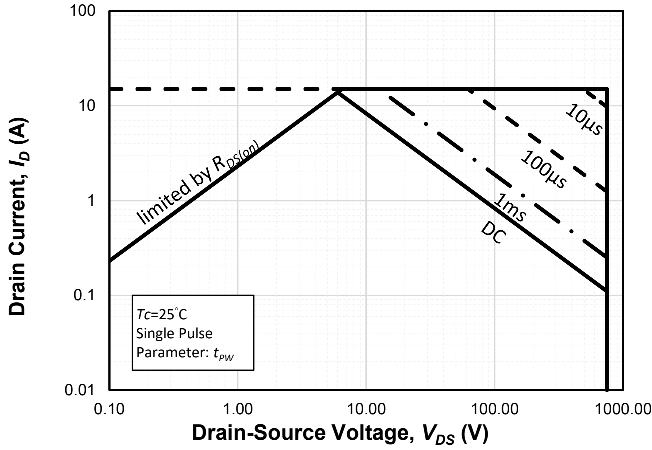

Fig. 6-1 Safe Operating Area at T_c=25˚C (TO-252)

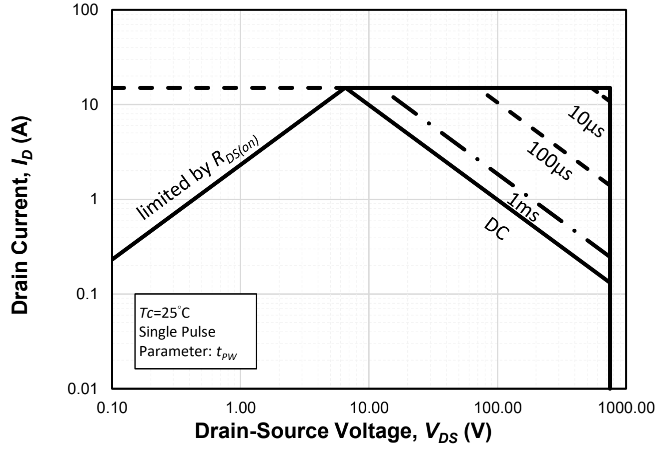

Fig. 6-2 Safe Operating Area at T_c=25˚C (PQFN 5x6)

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7. Safe Operating Area (100˚C)

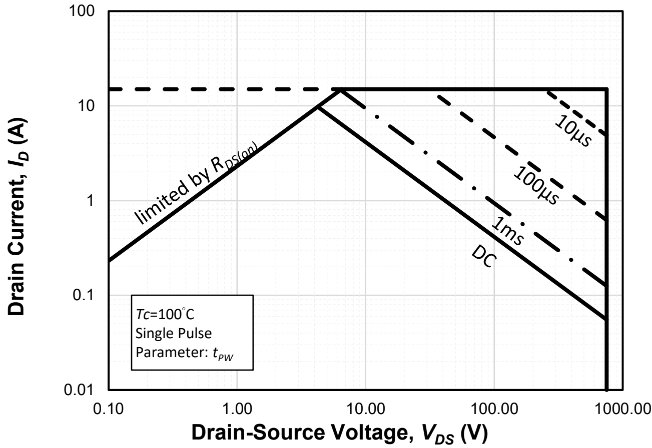

Fig. 7-1 Safe Operating Area at T_c=100˚C (TO-252)

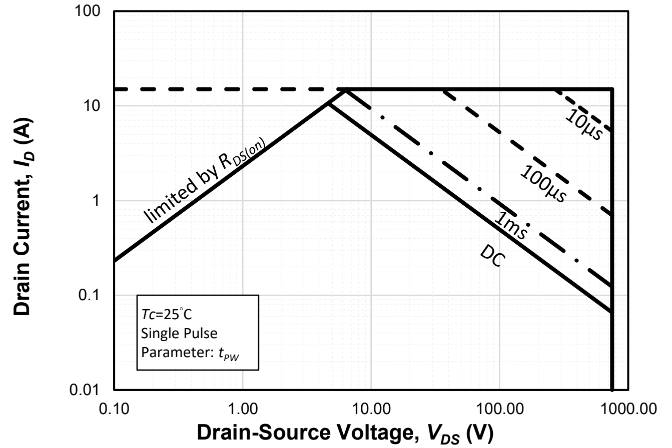

Fig. 7-2 Safe Operating Area at T_c=100˚C (PQFN 5x6)

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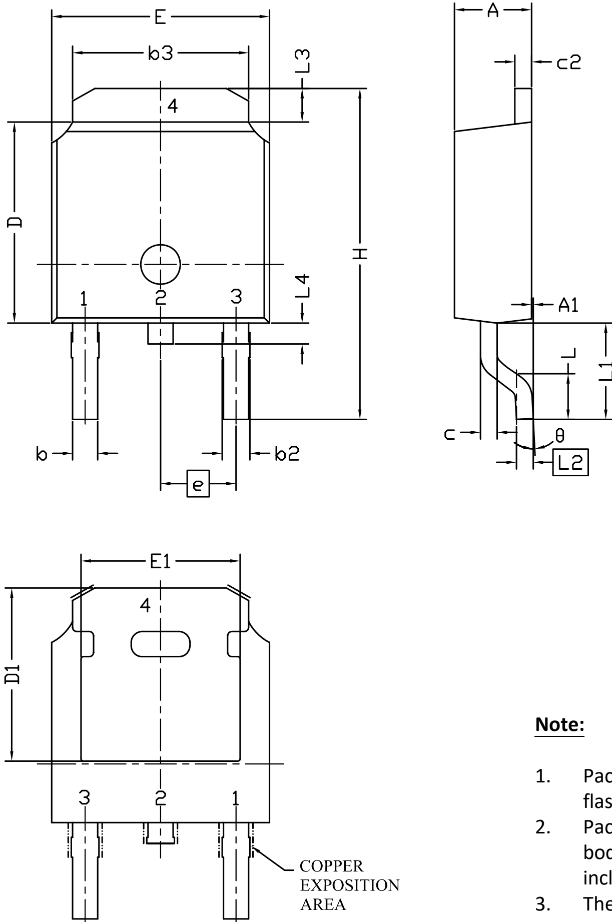
Package Outline (TO-252, DPAK)

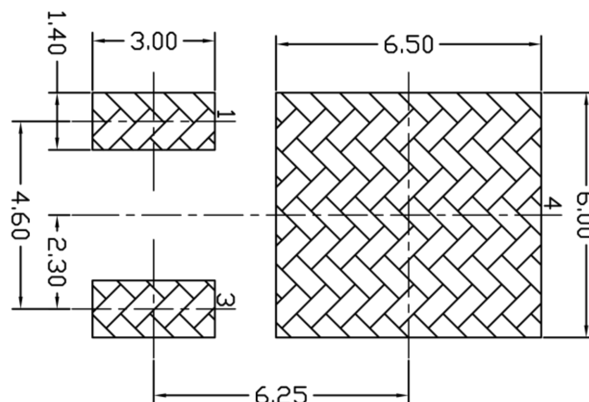


Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
E	6.40	6.60	6.73
L	1.40	1.52	1.77
L1	2.743 REF.		
L2	0.508 BSC.		
L3	0.89	--	1.27
L4	0.64	--	1.01
D	6.00	6.10	6.22
H	9.40	10.00	10.40
b	0.64	0.76	0.88
b2	0.77	0.84	1.14
b3	5.21	5.34	5.46
e	2.286 BSC.		
A	2.20	2.30	2.38
A1	0.00	--	0.127
c	0.46	0.50	0.60
c2	0.46	0.50	0.58
D1	5.21	--	--
E1	4.40	--	--
θ	0°	--	10°

Note:

1. Package body sizes exclude mold flash, protrusion, or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 0.10 mm per side.
2. Package body sizes determined at the outermost extremes of the plastic body exclusive of mold flash, gate burrs, and inter-lead flash, but including any mismatch between the top and bottom of the plastic body.
3. The package top may be smaller than the package bottom.
4. Dimension “b” does not include dambar protrusion. Allowable dambar protrusion shall be 0.10 mm total in excess of “b” dimension at the maximum material condition. The dambar cannot be located on the lower radius of the foot.

Land Pattern (Only for Reference)



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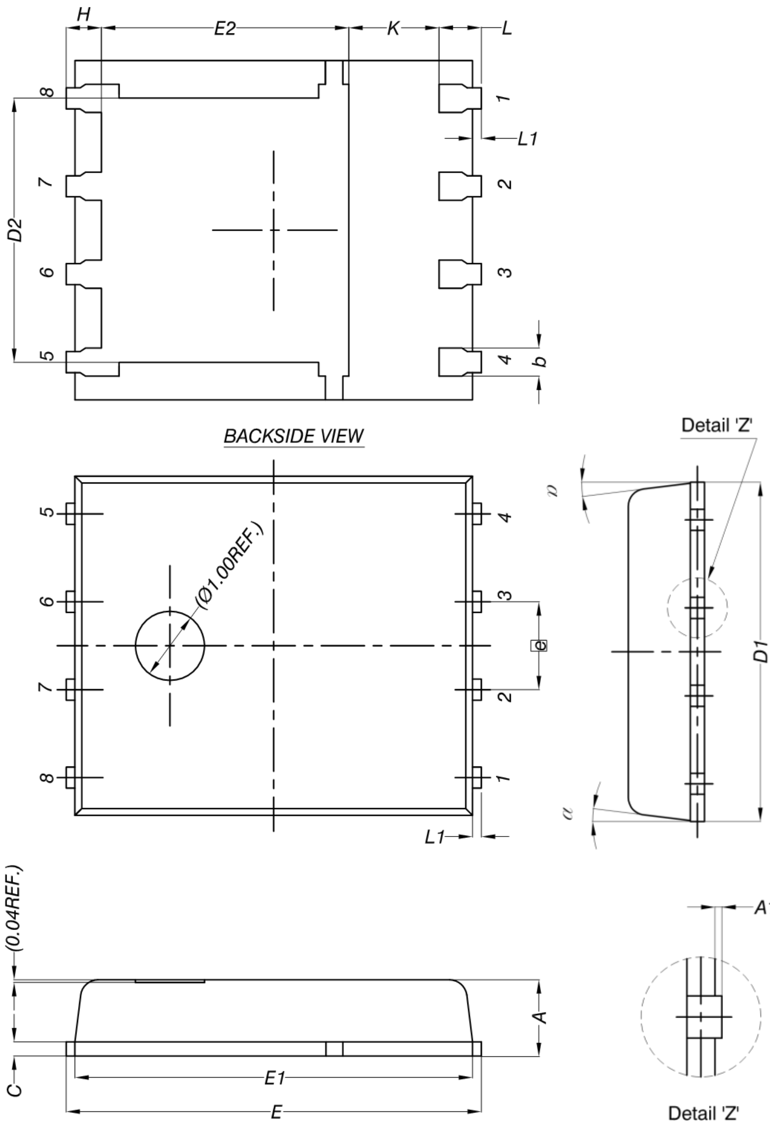
Package Outline (PQFN 5 x 6)

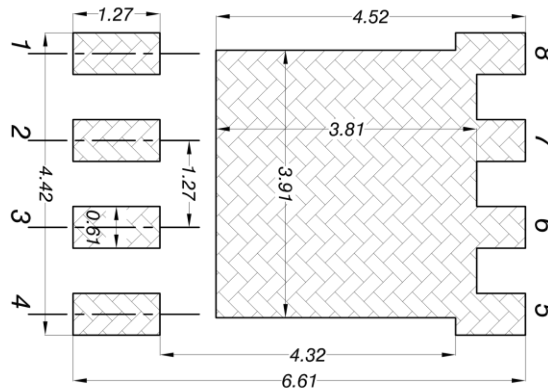


Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
A	0.90	1.00	1.10
A1	0	--	0.05
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	3.38	3.58	3.78
e		1.27 BSC.	
H	0.41	0.51	0.61
K	1.10	--	--
L	0.51	0.61	0.71
L1	0.06	0.13	020
α	0°	--	12°

Note:

1. Package body sizes exclude mold flash, protrusion, or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 0.10 mm per side
2. Package body sizes determined at the outermost extremes of the plastic body exclusive of mold flash, tie bar, tie bar burrs, gate burrs, and inter-lead flash, but including any mismatch between the top and bottom of the plastic body.
3. The package top may be smaller than the package bottom.

Land Pattern (Only for Reference)



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Revision History

Date	Revision	Changes
26.04	Preliminary	1st issue

Important Note (Disclaimer)

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This product is not designed or intended for use for applications in which the failure of the product could lead to personal injury, death or property damage, including but not limited to equipment used in medical systems, traffic communication or control systems, transportations (cars, ships, trains) and aerospace. FSS shall have no responsibility for any damages or injury arising from non-compliance with the recommended usage conditions provided herein.

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Hsinchu, Taiwan
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